



HGT65R110D2-NN

GaN Power Device

● Descriptions:

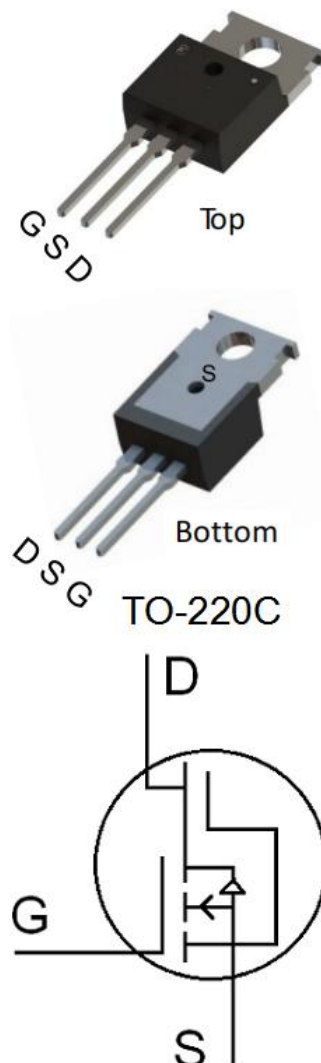
HGT65R110D2-NN is a 650V GaN power device with enhancement-mode operation and belongs to Huake GaN Series. It combines a low voltage Si MOSFET and a high voltage GaN device, compose cascode circuit. It is extremely easy to use, Fully compatible with conventional gate drivers. It features excellent gate noise immunity and is fully compatible with conventional gate drivers for Si MOSFET. HGT65R110D2-NN also features low on-resistance and low intrinsic capacitance with low reverse recovery charge, that enable the device to switch at extremely high frequency with low energy loss. The device is suitable for high voltage high power conversions with improved power density.

● Features:

- 21.0A, 650V, $R_{DS(on)(Typ)} = 110m\Omega @ V_{GS}=10V$
- Low gate charge
- Low C_{rss}
- Fast switching
- Easy to use
- Fully compatible with conventional gate drivers

● Application:

- High frequency switching mode power supply
- Servo motors
- Adapter



Absolute Maximum Ratings($T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	650	V
I_D	Drain Current - Continuous($T_c=25^\circ\text{C}$) note - Continuous($T_c=125^\circ\text{C}$) note	21	A
		9	A
I_{DM}	Pulse Drain Current -Pulse Width:10us	35	A
V_{GSS}	Gate-Source Voltage	± 20	V
P_D	Power Dissipation($T_c = 25^\circ\text{C}$)	125	W
T_j	Operating Junction Temperature	150	$^\circ\text{C}$
T_{stg}	Storage Temperature Range	-55 to +150	$^\circ\text{C}$

note:For increased stability at high current operation

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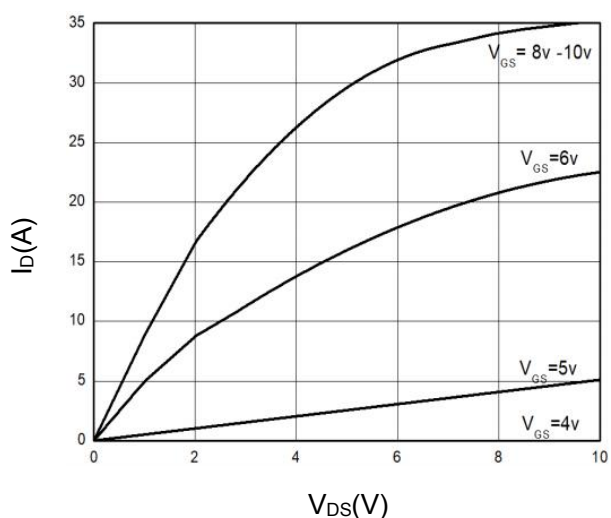
Electrical Characteristics(Tc=25°C unless otherwise noted)

Symbol	Parameter	Test Conditons	Min	Typ	Max	Unit
Off Characteristics						
V _{DSS}	Drain-source Voltage	V _{GS} =0V ,I _D =250μA	650	--	--	V
I _{DSS}	Drain-to-source Leakage current	V _{DS} =650V,V _{GS} =0V	--	--	10	μA
		V _{DS} =520V,T _c =125°C	--	--	100	μA
I _{GSSF}	Gate-Body Leakage Current,Forward	V _{GS} =+20V, V _{DS} =0V	--	--	1	μA
I _{GSSR}	Gate-Body Leakage Current,Reverse	V _{GS} =-20V, V _{DS} =0V	--	--	-1	μA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =1mA	3.0	3.9	5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} =10 V, I _D =1.0A	--	110	160	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =400V,V _{GS} =0V, f=1.0MHz	--	330	--	pF
C _{oss}	Output Capacitance		--	33	--	pF
C _{rss}	Reverse Transfer Capacitance		--	1.6	--	pF
Switching Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DS} = 400 V, I _D = 2.1 A, V _{GS} =0 to 10V, R _{G-on(ext)} =6.8Ω, R _{G-off(ext)} =2.2Ω, L=250μH	--	4.4	--	ns
t _r	Turn-On Rise Time		--	7.3	--	ns
t _{d(off)}	Turn-Off Delay Time		--	8	--	ns
t _f	Turn-Off Fall Time		--	30	--	ns
Q _g	Total Gate Charge	V _{DS} = 400 V, I _D =1.0 A, V _{GS} =0 to 10V,	--	6.9	--	nC
Q _{gs}	Gate-Source Charge		--	2	--	nC
Q _{gd}	Gate-Drain Charge		--	3	--	nC
Q _{oss}	Output Charge	V _{DS} =0 to 400V, V _{GS} = 0 V, f=1.0MHz,	--	48	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} =0V,I _S =10A	--	2.1	--	V
t _{rr}	Reverse Recovery Time	V _{DD} =400V, I _F =10 A, d I _F /dt=165A/μs	--	14	--	ns
Q _{rr}	Reverse Recovery Charge		--	6.5	--	nC

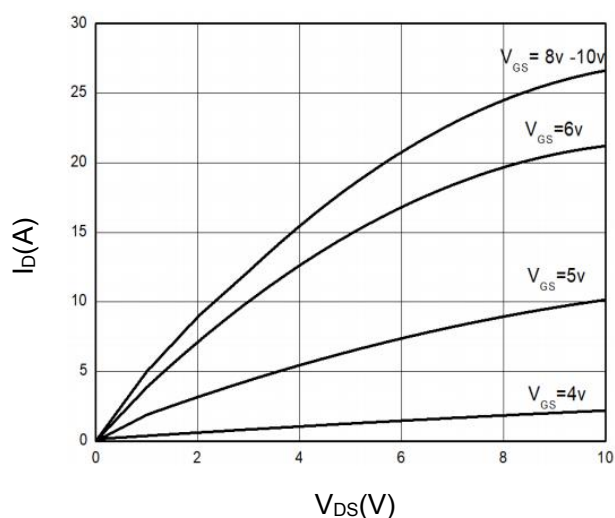
Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	1.0	$^\circ C/W$

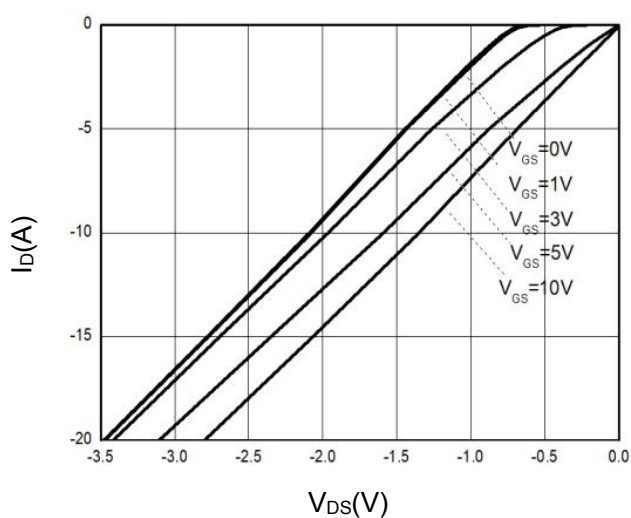
Typical Output Characteristic, $T_j=25^\circ\text{C}$



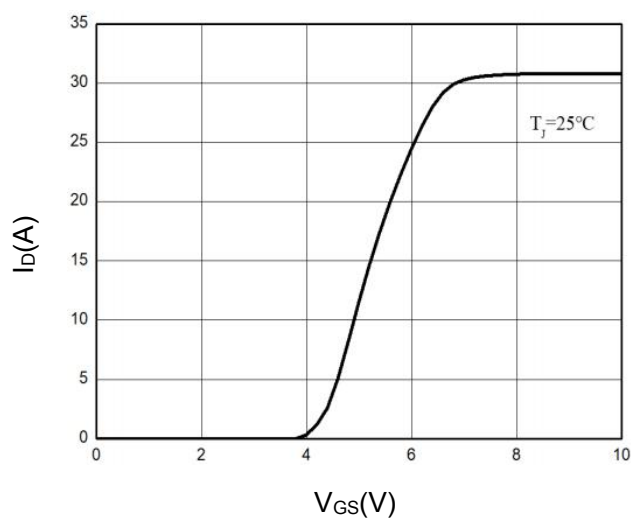
Typical Output Characteristic, $T_j=125^\circ\text{C}$



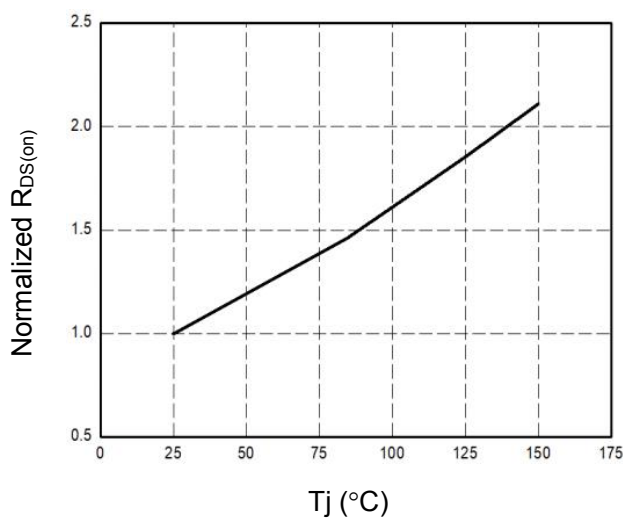
Channel Reverse Characteristic, $T_j=25^\circ\text{C}$



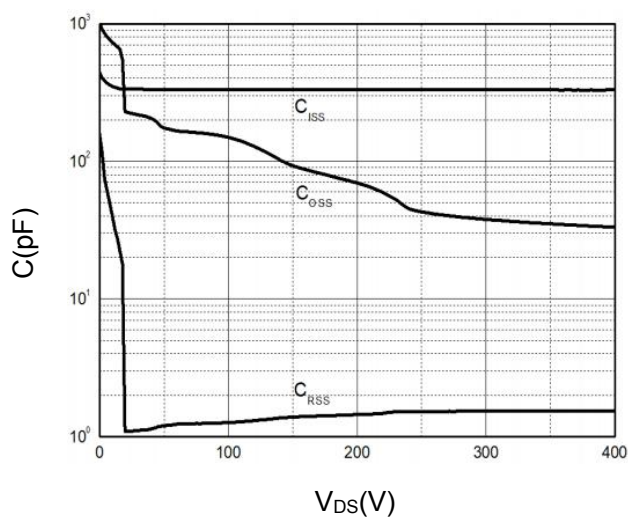
Typical Transfer Characteristics ($V_{DS}=10\text{V}$)



Normalized On-resistance



Typical Capacitance ($f=1\text{MHz}$)

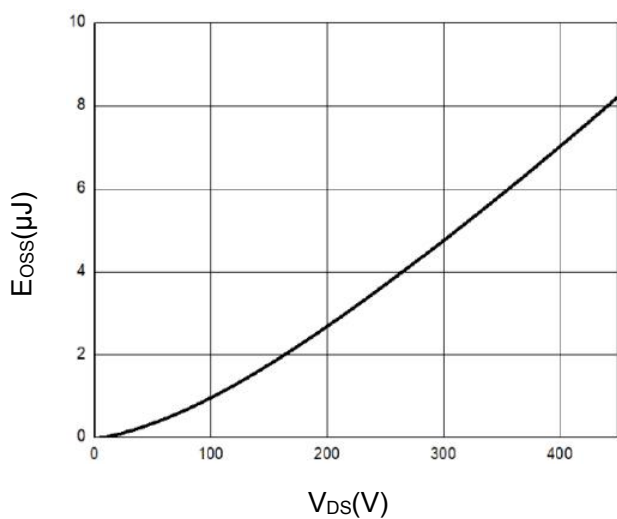




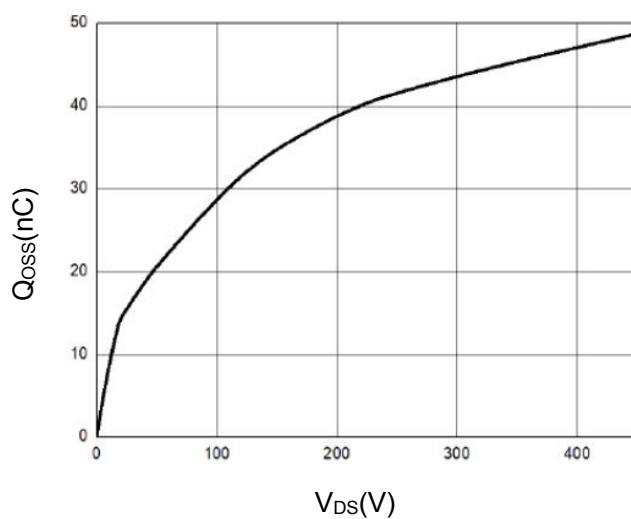
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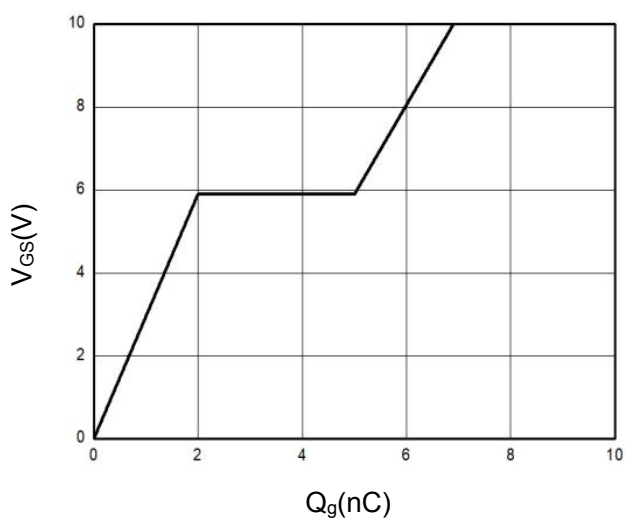
Typical Coss Stored Energy



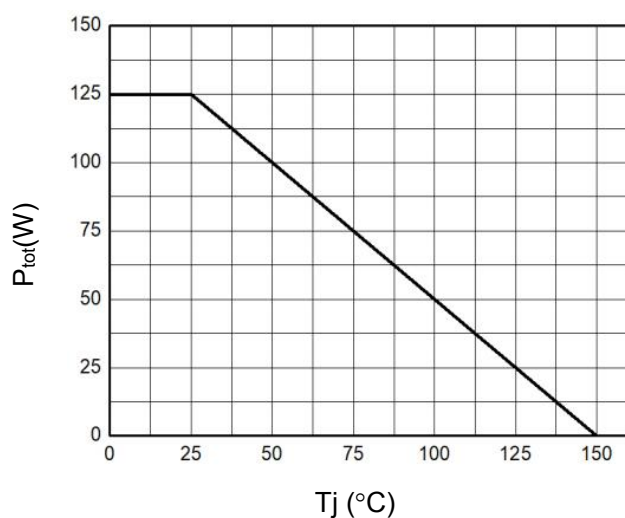
Typical Qoss



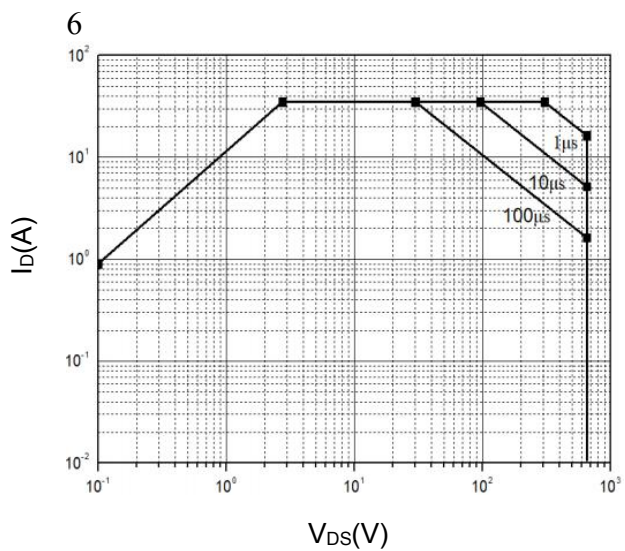
Typical Gate Charge ($V_{DS}=400V$, $I_D=1A$)



Power Dissipation



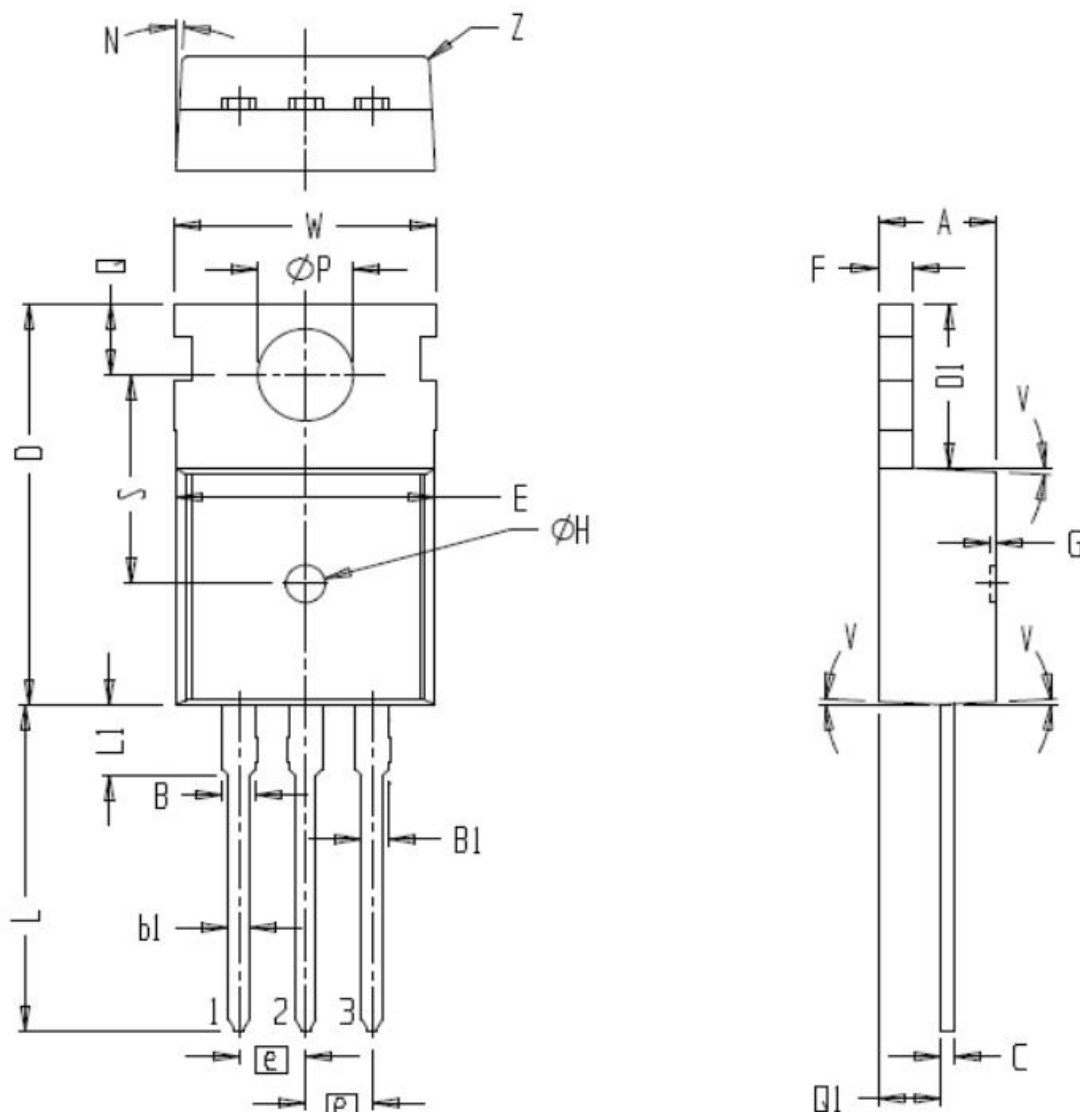
Safe Operating Area, $T_j=25^{\circ}C$



TO-220C Package Dimensions

UNIT: mm

SYMBOL	min	nom	max	SYMBOL	min	nom	max
A	4.10	4.50	4.90	E	9.40	9.90	10.40
B	1.17	1.32	1.47	e		2.54	
B1	0.90	1.06	1.22	F	1.15	1.30	1.45
b1	0.65	0.80	0.95	L	12.10	13.10	14.10
c	0.40	0.50	0.60	L1	2.50	3.00	3.50
D	14.70	15.70	16.80	Q	2.30	2.80	3.30
D1	6.00	6.50	7.00	Q1	1.90	2.40	2.90
W	9.50	10.00	10.50	ϕP	3.40	3.65	3.90
S		6.20		Z	0		0.20
ϕH		1.50		N		3 °	
G		0.10		V		3 °	



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注意事项：

- 1、在电路设计时请不要超过器件的最大额定值，否则会影响整机的可靠性。
- 2、**GaN Power Device**产品为静电敏感型器件，使用时应注意采取防静电保护措施，如佩戴防静电手环、设备接地等。
- 3、如需安装散热片，请注意控制扭力大小及散热片的平整度。
- 4、该规格书由华科公司制作，并可能不定期更改，恕不另行通知。
- 5、如有疑问，请及时联系我司销售代表。

版本履历表：

序号	版本号	修改时间	修改记录
1	V1.0	2023-12-20	首次发行